

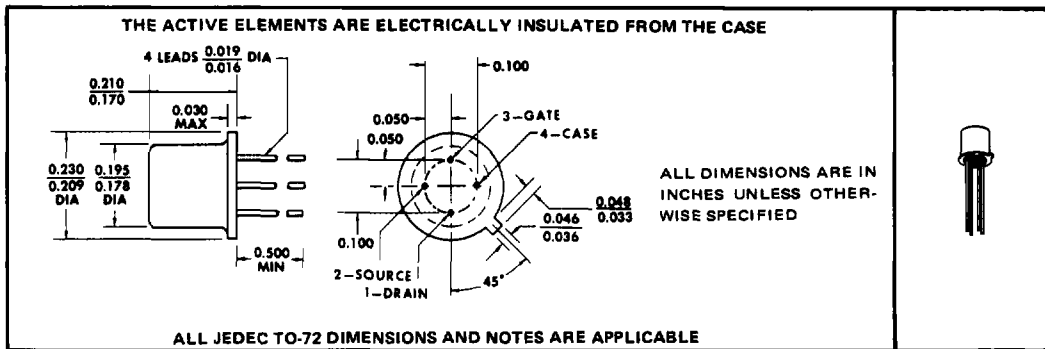
TYPES 2N5358 THRU 2N5364 N-CHANNEL SILICON JUNCTION FIELD-EFFECT TRANSISTORS

BULLETIN NO. DL-S 7111435, APRIL 1971

FOR SMALL-SIGNAL APPLICATIONS

- Narrow I_{DSS} and $V_{GS(off)}$ Ranges
- For Low-Noise Audio-Frequency Amplifier Applications
- For RF Amplifier Applications Thru 100 MHz
- For Chopper and Switching Applications

*mechanical data



*absolute maximum ratings at 25°C free-air temperature (unless otherwise noted)

Drain-Source Voltage	40 V
Reverse Gate-Source Voltage	-40 V
Continuous Forward Gate Current	10 mA
Continuous Device Dissipation at (or below) 25°C Free-Air Temperature (See Note 1)	300 mW
Storage Temperature Range	-65°C to 200°C
Lead Temperature 1/16 Inch from Case for 10 Seconds	300°C

NOTE 1: Derate linearly to 175°C free-air temperature at the rate of 2 mW/°C.

*JEDEC registered data. This data sheet contains all applicable registered data in effect at the time of publication.

USES CHIP JN51

TYPES 2N5358 THRU 2N5364

N-CHANNEL SILICON JUNCTION FIELD-EFFECT TRANSISTORS

*electrical characteristics at 25°C free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS†	2N5358		2N5359		UNIT
		MIN	MAX	MIN	MAX	
$V_{(BR)GSS}$ Gate-Source Breakdown Voltage	$I_G = -10 \mu A, V_{DS} = 0$	-40		-40		V
I_{GSS} Gate Reverse Current	$V_{GS} = -20 V, V_{DS} = 0$		-0.1		-0.1	nA
	$V_{GS} = -20 V, V_{DS} = 0, T_A = 150^\circ C$		-0.1		-0.1	μA
$V_{GS(off)}$ Gate-Source Cutoff Voltage	$V_{DS} = 15 V, I_D = 100 nA$	-0.5	-3	-0.8	-4	V
V_{GS} Gate-Source Voltage	$V_{DS} = 15 V, I_D = 50 \mu A$	-0.3	-1.5			V
	$V_{DS} = 15 V, I_D = 80 \mu A$			-0.4	-2	
I_{DSS} Zero-Gate-Voltage Drain Current	$V_{DS} = 15 V, V_{GS} = 0, \text{ See Note 2}$	0.5	1	0.8	1.6	mA
$ y_{fs} $ Small-Signal Common-Source Forward Transfer Admittance	$V_{DS} = 15 V, V_{GS} = 0, f = 1 \text{ kHz}, \text{ See Note 3}$	1	3	1.2	3.6	mmho
$ y_{os} $ Small-Signal Common-Source Output Admittance		10	10			μmho
C_{iss} Common-Source Short-Circuit Input Capacitance	$V_{DS} = 15 V, V_{GS} = 0, f = 1 \text{ MHz}, \text{ See Note 3}$	6		6		pF
C_{rss} Common-Source Short-Circuit Reverse Transfer Capacitance		2		2		pF
g_{fs} Small-Signal Common-Source Forward Transfer Conductance	$V_{DS} = 15 V, V_{GS} = 0, f = 100 \text{ MHz}, \text{ See Note 3}$	0.8		0.9		mmho

*electrical characteristics at 25°C free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS†	2N5360		2N5361		UNIT
		MIN	MAX	MIN	MAX	
$V_{(BR)GSS}$ Gate-Source Breakdown Voltage	$I_G = -10 \mu A, V_{DS} = 0$	-40		-40		V
I_{GSS} Gate Reverse Current	$V_{GS} = -20 V, V_{DS} = 0$		-0.1		-0.1	nA
	$V_{GS} = -20 V, V_{DS} = 0, T_A = 150^\circ C$		-0.1		-0.1	μA
$V_{GS(off)}$ Gate-Source Cutoff Voltage	$V_{DS} = 15 V, I_D = 100 nA$	-0.8	-4	-1	-6	V
V_{GS} Gate-Source Voltage	$V_{DS} = 15 V, I_D = 150 \mu A$	-0.5	-2.5			V
	$V_{DS} = 15 V, I_D = 250 \mu A$			-1	-5	
I_{DSS} Zero-Gate-Voltage Drain Current	$V_{DS} = 15 V, V_{GS} = 0, \text{ See Note 2}$	1.5	3	2.5	5	mA
$ y_{fs} $ Small-Signal Common-Source Forward Transfer Admittance	$V_{DS} = 15 V, V_{GS} = 0, f = 1 \text{ kHz}, \text{ See Note 3}$	1.4	4.2	1.5	4.5	mmho
$ y_{os} $ Small-Signal Common-Source Output Admittance		20	20			μmho
C_{iss} Common-Source Short-Circuit Input Capacitance	$V_{DS} = 15 V, V_{GS} = 0, f = 1 \text{ MHz}, \text{ See Note 3}$	6		6		pF
C_{rss} Common-Source Short-Circuit Reverse Transfer Capacitance		2		2		pF
g_{fs} Small-Signal Common-Source Forward Transfer Conductance	$V_{DS} = 15 V, V_{GS} = 0, f = 100 \text{ MHz}, \text{ See Note 3}$	1.4		1.7		mmho

NOTES: 2. This parameter must be measured using pulse techniques. $t_w = 300 \mu s$, duty cycle $\leq 2\%$.

3. These parameters must be measured with bias conditions applied for less than 5 seconds to avoid overheating.

*JEDEC registered data

†The fourth lead (case) is connected to the source for all measurements.

TYPES 2N5358 THRU 2N5364

N-CHANNEL SILICON JUNCTION FIELD-EFFECT TRANSISTORS

*electrical characteristics at 25°C free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS†	2N5362		2N5363		2N5364		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	
V(BR)GSS Gate-Source Breakdown Voltage	I _G = -10 μA, V _{DS} = 0	-40		-40		-40		V
I _{GSS} Gate Reverse Current	V _{GS} = -20 V, V _{DS} = 0		-0.1		-0.1		-0.1	nA
	V _{GS} = -20 V, V _{DS} = 0, T _A = 150°C		-0.1		-0.1		-0.1	μA
V _{GS(off)} Gate-Source Cutoff Voltage	V _{DS} = 15 V, I _D = 100 nA	-2	-7	-2.5	-8	-2.5	-8	V
V _{GS} Gate-Source Voltage	V _{DS} = 15 V, I _D = 0.4 mA	-1.3	-5					V
	V _{DS} = 15 V, I _D = 0.7 mA			-2	-6			
	V _{DS} = 15 V, I _D = 0.9 mA					-2	-6	
I _{DSS} Zero-Gate-Voltage Drain Current	V _{DS} = 15 V, V _{GS} = 0, See Note 2	4	8	7	14	9	18	mA
y _{fs} Small-Signal Common-Source Forward Transfer Admittance	V _{DS} = 15 V, V _{GS} = 0, f = 1 kHz, See Note 3	2	5.5	2.5	6	2.7	6.5	mmho
y _{os} Small-Signal Common-Source Output Admittance			40		40		60	μmho
C _{iss} Common-Source Short-Circuit Input Capacitance	V _{DS} = 15 V, V _{GS} = 0, f = 1 MHz, See Note 3		6		6		6	pF
C _{rss} Common-Source Short-Circuit Reverse Transfer Capacitance			2		2		2	pF
g _{fs} Small-Signal Common-Source Forward Transfer Conductance	V _{DS} = 15 V, V _{GS} = 0, f = 100 MHz, See Note 3	1.9		2.1		2.2		mmho

*operating characteristics at 25°C free-air temperature

PARAMETER	TEST CONDITIONS†	ALL TYPES		UNIT
		MIN	MAX	
NF Common-Source Spot Noise Figure	V _{DS} = 15 V, V _{GS} = 0, f = 100 Hz, R _G = 1 MΩ, See Note 3		2.5	dB

NOTES: 2. This parameter must be measured using pulse techniques. t_w = 300 μs, duty cycle ≤ 2%.

3. These parameters must be measured with bias conditions applied for less than 5 seconds to avoid overheating.

*JEDEC registered data

†The fourth lead (case) is connected to the source for all measurements.

TYPICAL CHARACTERISTICS

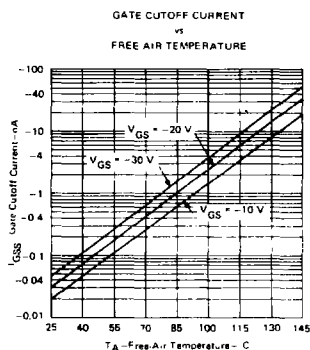


FIGURE 1

NOMINAL CHARACTERISTIC VALUES FOR NORMALIZED CURVES AT V_{GS} = 15 V, T_A = 25°C

PARAMETER	I _{DSS} (mA)	V _{GS} (V)	y _{fs} (mmho)
Conditions	V _{GS} = 0	I _D = 100 μA	V _{GS} = 0, f = 1 kHz
2N5362	6	-2.0	4.3
2N5363	10	-3.0	4.7
2N5364	15	-4.0	5.2

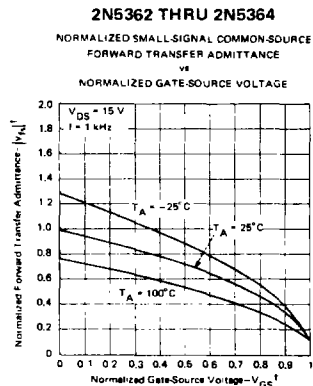


FIGURE 2

$$\text{†Normalized } V_{GS} = \frac{V_{GS}}{V_{GS} \text{ at } I_D = 100 \mu\text{A}, T_A = 25^\circ\text{C}}; \quad \text{Normalized } |y_{fs}| = \frac{|y_{fs}|}{|y_{fs}| \text{ at } V_{GS} = 0, T_A = 25^\circ\text{C}}$$